

Search Notes**Application/Control No.**

09/769,908

Examiner

John L. Shew

Applicant(s)/Patent under Reexamination

MATSUHIRA ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	216-218	3/17/2006	JS
	228,237		
	238.1		
	255-258		
	295,351		
370	352,355	3/20/2006	JS
	389,392		
	395.1		
	395.31		
	395.32		
	400		
	401		
	402		
	403-404		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
370	395.31	3/20/2006	JS
370	218	3/20/2006	JS
709	239	3/20/2006	JS

Search Notes (continued) 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/769,908	MATSUHIRA ET AL.
	Examiner John L. Shew	Art Unit 2616

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner